

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/660,550	YOKONUMA ET AL.	
Examiner	Art Unit	
Tuan H. Le	2622	

	SEARCHED				
Class	Subclass	Date	Examiner		
348	222.1,277, 279,909.1, 231.1	11/21/2006	TL		
358	405,406	11/21/2006	TL		
358	434,439	11/21/2006	TL		
386	109,120	11/21/2006	TL		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor name search	11/21/2006	TL	
US-PGPUB,USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	11/21/2006	TL	
INSPEC (same search key as in EAST)	11/21/2006	TL	
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